



## Fault Localization Techniques for Software Systems

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Deadline for manuscript  
submissions:

**closed (15 February 2024)**

### Message from the Guest Editor

Dear Colleagues,

Detecting faults in software is known as fault localization. Modern software is larger and more complex than ever before, and is a major component of any computer system. There is a strong demand for techniques that can guide software developers to the locations of faults in a program with minimal human intervention. Therefore, researchers are invited to submit their research on this topic to this Special Issue. Potential topics may include, but are not limited to:

- Strategies for effective and efficient program debugging, fault localization, and repair;
- Defect prediction;
- Debugging and repair of multi-{core, process, or threaded};
- Integrating debugging and repair with other software development and maintenance activities;
- Empirical studies, benchmarking, and industrial best practices;
- Applications and tools;
- Visualizations for fault localization;
- Deep learning-based fault localization;
- Artificial Intelligence techniques and fault localization;
- Debugging pervasive, ubiquitous, service-oriented, cloud computing collaborative, distributed, embedded, real-time, high-performance, highly dependable, and intelligent multimedia systems.





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## Message from the Editor-in-Chief

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